

Is Now Part of



ON Semiconductor®

To learn more about ON Semiconductor, please visit our website at <u>www.onsemi.com</u>

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor dates sheds, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor dates sheds and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights of others. ON Semiconductor products are not designed, intended, or authorized for use on similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor and its officers, employees, subsidiaries, affliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out or i, directly or indirectly, any lange of the applicatio customer's to unauthorized use, even if such claim alleges that ON Semiconductor was negligent regarding the

March 1999



FDC6305N

Dual N-Channel 2.5V Specified PowerTrench[™] MOSFET

General Description

These N-Channel low threshold 2.5V specified MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain low gate charge for superior switching performance.

Applications

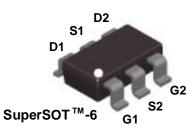
- Load switch
- DC/DC converter
- Motor driving

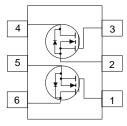
Features

• 2.7 A, 20 V.
$$R_{DS(ON)} = 0.08 \ \Omega @ V_{GS} = 4.5 \ V$$

 ${\sf R}_{\rm DS(ON)}$ = 0.12 Ω @ ${\sf V}_{\rm GS}$ = 2.5 V

- Low gate charge (3.5nC typical).
- Fast switching speed.
- High performance trench technology for extremely low $\rm R_{\rm DS(ON)}.$
- SuperSOTTM-6 package: small footprint (72% smaller than standard SO-8); low profile (1mm thick).





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		20	V
V _{GSS}	Gate-Source Voltage		<u>+</u> 8	V
ID	Drain Current - Continuous	(Note 1a)	2.7	А
	- Pulsed		8	
P _D	Power Dissipation for Single Operation	(Note 1a)	0.96	W
		(Note 1b)	0.9	
		(Note 1c)	0.7	
T _J , T _{stg}	Operating and Storage Junction Temperature Range		-55 to +150	۰C
Therma	I Characteristics			
R _{θJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	130	∘C/W
R _{AJC}	Thermal Resistance, Junction-to-Case	(Note 1)	60	°C/W

Package Outlines and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
 .305	FDC6305N	7"	8mm	3000 units

©1999 Fairchild Semiconductor Corporation

Parameter	Test Conditions	Min	Тур	Max	Units
racteristics					
Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_D = 250 \mu A$	20			V
Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25° C		14		mV/∘C
Zero Gate Voltage Drain Current	$V_{DS} = 16 V, V_{GS} = 0 V$			1	μA
Gate-Body Leakage Current, Forward	$V_{GS} = 8 V, V_{DS} = 0 V$			100	nA
Gate-Body Leakage Current, Reverse	V_{GS} = -8 V, V_{DS} = 0 V			-100	nA
acteristics (Note 2)					
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	0.4	0.9	1.5	V
Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-2.7		mV/∘C
Static Drain-Source On-Resistance	$V_{GS} = 4.5, I_D = 2.7 \text{ A}$ $V_{GS} = 4.5 I_D = 2.7 \text{ A}, T_J = 125^{\circ}\text{C}$ $V_{GS} = 2.5 \text{ V}, I_D = 2.2 \text{ A}$		0.060 0.095 0.085	0.080 0.128 0.120	Ω
On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$	6			А
Forward Transconductance	$V_{DS} = 5 V, I_D = 2.7 A$		8		S
c Characteristics					
Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$		310		pF
Output Capacitance	f = 1.0 MHz		80		pF
Reverse Transfer Capacitance			40		pF
ng Characteristics (Note 2)					
Turn-On Delay Time	$V_{DD} = 10 V, I_D = 1 A,$		5	15	ns
Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, \text{ R}_{GEN} = 6 \Omega$	-	8.5	17	ns
Turn-Off Delay Time	1		11	20	ns
Turn-Off Fall Time	1		3	10	ns
Total Gate Charge	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 2.7 \text{ A},$		3.5	5	nC
-	V _{GS} = 4.5 V		0.55		nC
Gate-Source Charge					
Gate-Source Charge Gate-Drain Charge			0.95		nC
Gate-Drain Charge	d Maximum Ratings		0.95		nC
° °	-		0.95	0.8	nC A
	Coefficient Zero Gate Voltage Drain Current Gate-Body Leakage Current, Forward Gate-Body Leakage Current, Reverse acteristics (Note 2) Gate Threshold Voltage Gate Threshold Voltage Temperature Coefficient Static Drain-Source On-Resistance On-State Drain Current Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Characteristics (Note 2) Turn-On Rise Time Turn-On Rise Time Turn-Off Delay Time	CoefficientVDS $= 16 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ Zero Gate Voltage Drain Current $V_{DS} = 16 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ Gate-Body Leakage Current, Forward $V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{DS} = 10 \text{ L}, Referenced to 25^{\circ}C$ Gate Threshold Voltage Temperature Coefficient $V_{GS} = 4.5 \text{ I}_D = 2.7 \text{ A}$ Static Drain-Source On-Resistance $V_{GS} = 4.5 \text{ V}, D_D = 2.7 \text{ A}$ On-State Drain Current $V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$ Forward Transconductance $V_{DS} = 5 \text{ V}, I_D = 2.7 \text{ A}$ CharacteristicsInput CapacitanceInput Capacitance $V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ Reverse Transfer CapacitanceVDD = 10 \text{ V}, I_D = 1 \text{ A}, V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \OmegaTurn-On Rise Time $V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$ Turn-Off Delay TimeVDD = 10 \text{ V}, I_D = 1 \text{ A}, V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega	CoefficientVDSInterventVDSInterventZero Gate Voltage Drain CurrentVDS $V_{GS} = 0 V$ InterventGate-Body Leakage Current, ReverseVGS $V_{DS} = 0 V$ InterventGate-Body Leakage Current, ReverseVGS $V_{DS} = 0 V$ InterventGate Threshold VoltageVDS $V_{DS} = V_{GS}, I_D = 250 \mu A$ 0.4 Gate Threshold VoltageVDS $V_{DS} = V_{GS}, I_D = 250 \mu A$ 0.4 Gate Threshold VoltageVDS $V_{DS} = V_{GS}, I_D = 250 \mu A$ 0.4 Gate Threshold VoltageVDS $V_{DS} = 10 \mu A$, Referenced to $25^{\circ}C$ $V_{CS} = 4.5, I_D = 2.7 A$ Static Drain-SourceVGS $V_{GS} = 4.5, I_D = 2.7 A$ $V_{GS} = 2.5 V, I_D = 2.2 A$ On-ResistanceVGS $V_{DS} = 5 V, I_D = 2.7 A$ $V_{CS} = 2.5 V, I_D = 2.2 A$ On-State Drain CurrentVGS $V_{DS} = 5 V, I_D = 2.7 A$ $V_{DS} = 5 V, I_D = 2.7 A$ CharacteristicsInput Capacitance $V_{DS} = 5 V, I_D = 2.7 A$ $V_{DS} = 5 V, I_D = 2.7 A$ Input CapacitanceVDS $V_{DS} = 10 V, V_{CS} = 0 V, I_D = 1.0 M Hz$ $V_{DS} = 10 V, V_{CS} = 0 V, I_D = 1.0 M Hz$ Characteristics(Note 2) $V_{DD} = 10 V, I_D = 1 A, V_{CS} = 0 Q$ $V_{CS} = 4.5 V, R_{GEN} = 6 \Omega$ Turn-On Delay TimeVDS = 10 V, V_GS = 6 \Omega $V_{CS} = 4.5 V, R_{GEN} = 6 \Omega$	CoefficientVDS16 V, VGS0Zero Gate Voltage Drain Current $V_{DS} = 16$ V, $V_{GS} = 0$ V0Gate-Body Leakage Current, Forward $V_{GS} = 8$ V, $V_{DS} = 0$ V0Gate-Body Leakage Current, Reverse $V_{GS} = -8$ V, $V_{DS} = 0$ V0cateristics (Note 2)Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = 250 \ \mu$ A0.40.9Gate Threshold Voltage $I_D = 250 \ \mu$ A, Referenced to 25°C-2.7Temperature Coefficient $V_{GS} = 4.5$, $I_D = 2.7$ A, $T_J = 125°C$ 0.060On-Resistance $V_{GS} = 4.5$, $I_D = 2.7$ A, $T_J = 125°C$ 0.085On-State Drain Current $V_{GS} = 4.5$ V, $V_{DS} = 5$ V6Forward Transconductance $V_{DS} = 5$ V, $I_D = 2.7$ A8CharacteristicsInput Capacitance $V_{DS} = 10$ V, $V_{GS} = 0$ V,310Output Capacitance $V_{DS} = 10$ V, $V_{GS} = 0$ V,40GCharacteristics (Note 2)Turn-On Delay Time $V_{DD} = 10$ V, $I_D = 1$ A,5Turn-On Rise Time $V_{GS} = 4.5$ V, $R_{GEN} = 6$ Ω 8.5	$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$

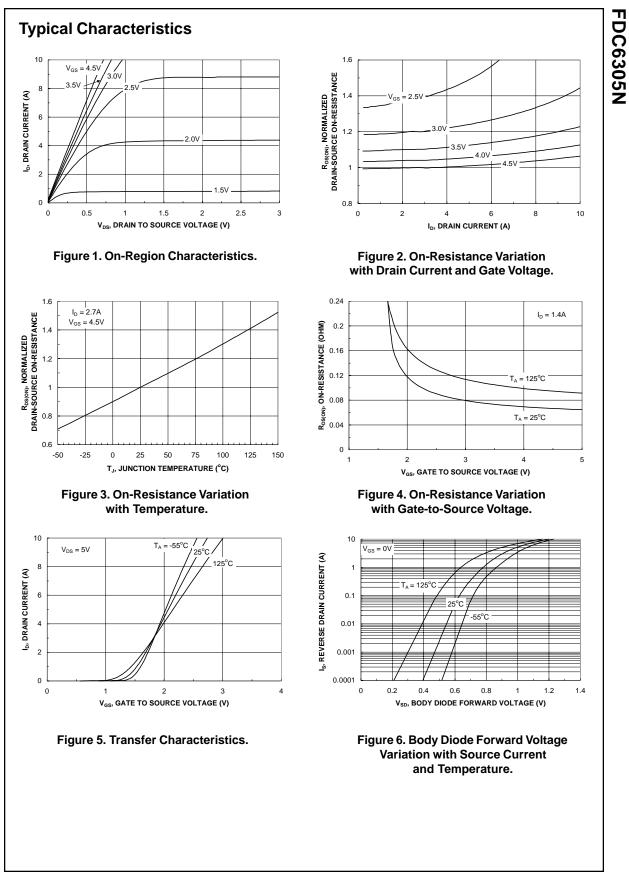




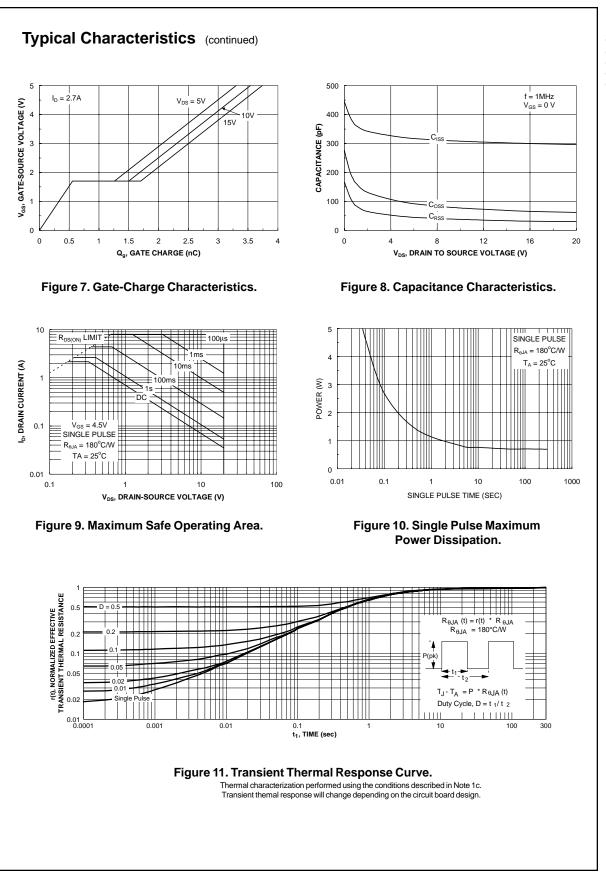
Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%

FDC6305N



FDC6305N, Rev. C



FDC6305N

FAIRCHILD

TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACEx™
CoolFET™
CROSSVOLT™
E ² CMOS [™]
FACT™
FACT Quiet Series™
FAST [®]
FASTr™
GTO™
HiSeC™

ISOPLANAR[™] MICROWIRE[™] POP[™] PowerTrench[®] QFET[™] QS[™] Quiet Series[™] SuperSOT[™]-3 SuperSOT[™]-6 SuperSOT[™]-8

TinyLogic™ UHC™ VCX™

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user. 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

www.fairchildsemi.com